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QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>1010051689</u>	Prepared by <u>NH.</u>	Tracking Number <u>05884744</u>	
Examiner-GAU <u>Zarnela-2829</u>	Date <u>1-29-04</u>	Week Date <u>01/05/04</u>	
No. of queries <u>1</u>		IFW	

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE
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d. Other Missing Text	
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g. Brief Description	
h. Sequence Listing	
i. Appendix	
j. Amendments	
k. Other	
CLAIMS	
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k. Other	
RESPONSE	
	<p><u>1449 int. m</u></p> <p><u>Done 5/4/04</u></p>
	initials <u>24</u>

INFORMATION DISCLOSURE CITATION
(37 CFR 1.97)

Application Number
Filing Date
First Named Inventor Rutten
Group Art Unit
Examiner Name
Attorney Docket US 018180

11036 U.S. PAT. & TM. OFF. 10/005689 11/08/01

U.S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	Patent Number	Date	Name	Class	Sub-Class	Filing Date, If Approp.
2A	AA	6,075,373	13 June 2000	Iino			
	AB	6,169,410 B1	2 January 2001	Grace et al.			
	AC	(copending application) "PRECONDITIONED INTEGRATED CIRCUIT FOR INTEGRATED CIRCUIT TESTING"		Rutten			(concurrent)
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

Examiner's Initials	Cite No.	Patent Number	Date	Country	Class	Sub-Class	Translation
2A	AJ	EP 0 755 071 A2	18 July 1996	Europe			Yes No
	AK						
	AL						
	AM						

Other (Include Author, Title, Date, Pertinent Pages, Etc.)

Examiner's Initials	Cite No.	
2A	AN	"Introducing WOW Technology", http://www.formfactor.com/about/wow/wow_pg2.html
	AO	"Introducing WOW Technology", http://www.formfactor.com/about/wow/wow_pg5.html
	AP	"Focus on FormFactor", THE FINAL TEST REPORT, Vol. 12, No. 09, September 2001, Ikonix Corp. P.O. Box 1938, Lafayette, CA 94549-1938
	AQ	"Flip-Chip Bonding on 6-um Pitch using Thin-Film Microspring Technology", Donald L. Smith et al., Xerox Palo Alto Research Center, Proceedings, 48 th Electronic Components and Technology Conference, IEEE, May 1998.
	AR	

Examiner

Tina Nguyen

Date Considered

5/4/04

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Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to the Applicant.